Application/Control No. Applicant(s)/Patent Under Reexamination 09/431,157 YOON ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 David Y. Chung 2871 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,285,431 09-2001 349/143 Lyu et al. US-В С US-US-D Ε US-F US-G US-US-Н US-1 J US-Κ US-US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Τ **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W Х

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